# Effect of Fatigue under Transverse Compressive Stress on Slitted Y-Ba-Cu-O Coated Conductors

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Abstract— The slitting of wide Y-Ba-Cu-O coated-conductor tapes to a desirable width for applications allows a considerable reduction in conductor manufacturing cost. Localized damage induced at the slit edges may be tolerated provided that mechanical cracks formed in the ceramic layers do not propagate deeper inside the conductor due to mechanical forces and thermal cycling that the strand will be subjected to in actual applications. In order to evaluate the effect of slitting, we used fatigue cycling under transverse compressive stress. These tests simulate conditions in applications such as rotating machinery and industrial magnets. Conductors measured had a rollingassisted biaxially textured Ni-W substrate (RABiTS), or a Hastalloy-C substrate with an ion-beam assisted deposition (IBAD) buffer template. Samples were fabricated with or without a Cu protection layer. Furthermore, specimen with the protection layer had Cu added either before or after slitting. For all these geometries, the critical-current exhibited no significant degradation during fatigue testing up to 150 MPa transverse compressive stress and 20,000 cycles. Nevertheless, the results obtained do not guarantee that slitting is harmless to the conductor performance under all experimental conditions.

*Index Terms*—Coated conductors, critical current density, crack propagation, fatigue cycling, IBAD, RABiTS, slitting, stress, transverse compression, Y-Ba-Cu-O.

### I. INTRODUCTION

THE fast advancement in the development of yttrium-barium-copper-oxide (YBCO) coated conductors brings more promises than ever that these conductors will play an important role in modernizing the aging electric transmission and delivery systems to satisfy the growing demand for electricity in several parts of the world [1]-[3].

Manufacturers have opted to fabricate wide coatedconductor tapes (up to 40 mm), and then slit them to a width of typically 4 mm desired for most applications. This technique provides a considerable reduction in conductor

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manufacturing cost but induces damage at the slit edges, which results in a reduction (up to  $\sim 15$  percent) of the critical-current density  $J_c$ . However, the benefits of slitting outweigh the slight reduction in  $J_c$ , provided that mechanical cracks formed in the ceramic layers at the tape edges do not propagate deeper into the conductor under the mechanical forces and thermal cycling that the strand will be subjected to in actual applications. Evaluation of the slitting damage is crucial at this point of development before scaling up the production of coated conductors to kilometers lengths.

In order to evaluate the effect of slitting, we used fatigue cycling under transverse compressive stress, since previous experiments had shown this to induce crack propagation in earlier YBCO coated conductors [4]-[5].  $J_c$  was measured in samples subjected to 20,000 fatigue cycles of transverse compressive stress up to 150 MPa, which is higher than the 100 MPa benchmark commonly agreed upon for several applications. These tests simulate conditions in applications such as rotating machinery and industrial magnets, and evaluate whether fatigue exacerbates cracks by propagating them into the conductor. The measurements could also help discriminate between different slitting techniques and assess the influence of coated-conductor configurations on crack propagation. In addition, these data provide an updated evaluation of the effect of transverse compression on transport properties in the newer coated-conductor geometries as compared to our previous reports [4]-[7].

### II. EXPERIMENTAL PROCEDURE

# A. Sample Preparation

Samples were fabricated either with rolling-assisted biaxially textured Ni-5at.% W substrates (RABiTS) [8] or ion-beam-assisted deposition (IBAD) on Hastelloy C-276 substrates [9]. In this paper, RABiTS and IBAD samples are designed with the prefix 'A' and 'B', respectively. Table I lists the 11 samples measured and gives a brief summary of the results obtained.

For the RABiTS, YBCO (0.8  $\mu$ m-thick) was deposited on a 75  $\mu$ m-thick buffered Ni-5at.%W substrate (up to 40 mm wide) by the use of a BaF<sub>2</sub> *ex situ* process with metal-organic deposition precursors (MOD). A 3  $\mu$ m-thick layer of Ag was added to the YBCO. Two types of samples were investigated

Table I: Description of RABiTS and IBAD YBCO-coated conductors tested and summary of the results obtained on the effect of transverse-compressive stress and fatigue cycling. Measurements were performed at 76 K in self-field.

Sample No.	Fabrication process	Substrate; $t_S^a$ (µm)	t <sub>Cu</sub> a per side (μm)	Process of Cu addition and slitting	Maximum stress $\sigma_{TM}$ (MPa)	$J_{\rm c}$ degradation from monotonic loading <i>to</i> $\sigma_{ m TM}$	Number of fatigue cycles applied	$J_{\rm c}$ degradation from fatigue cycling
A1	RABiTS/ MOD	Ni-5at.%W; 75	75	Neutral-axis; tape slitted after Cu-lamination	75	2 %	21,000	1.5 %
A2	"	"	75	"	100	< 1 %	20,000	< 1 %
A3	"	"	75	"	100	< 1 %	20,050	< 1 %
A4	"	"	75	"	150	< 1 %	20,000	< 1 %
A5	"	"	75	"	150	1.4 %	20,000	< 1 %
A6	"	"	50	3-ply; tape slitted <i>before</i> Cu-lamination	150	< 1 %	20,000	< 1 %
A7	"	"	50	"	150	< 1 %	20,000	< 1 %
B1	IBAD/ MOCVD	Hastelloy C-276; 100	0	Not Cu-plated; tape slitted	100	< 1 %	20,200	< 1 %
B2	"	"	20	Cu-plated on YBCO and substrate sides; tape slitted <i>after</i> Cu-plating	100	< 1 %	20,000	< 1 %
В3	"	"	20	Cu-plated <i>all</i> sides; tape slitted <i>before</i> Cu-plating	100	< 1 %	20,000	< 1 %
B4	"	"	20	"	150	< 1 %	20,000	< 1 %

 $<sup>^{</sup>a}t_{S}$ ,  $t_{Cu}$ : thicknesses of substrate and Cu layers, respectively.

in this work: a) the neutral-axis specimens where a 75  $\mu$ m-thick Cu foil was soldered to the YBCO side of the tape. Then the conductor was slit to a width of 4 mm (samples A1-A5); b) the 3-ply samples where the tape was first slit to a 4 mm width, and then two 50  $\mu$ m-thick Cu foils (4.4 mm wide each) were laminated to the conductor, one foil on the YBCO side and the other on the substrate side (samples A6 and A7).

IBAD samples include a 100  $\mu$ m-thick Hastelloy C-276 substrate (up to 12 mm wide) with an IBAD yttria-stabilized zirconia (YSZ) buffer template, on top of which an YBCO layer (1.1  $\mu$ m-thick) was grown by the use of metal-organic chemical vapor deposition (MOCVD). A 3  $\mu$ m-thick layer of Ag was added to YBCO. Three types of samples were studied: a) a sample slit to a 4 mm width, not Cu-plated (sample B1); b) a sample electroplated with a 20  $\mu$ m-thick Cu layer on each of the YBCO and substrate sides – thereafter the sample was slitted to 4 mm width (sample B2); c) samples were first slit to a width of 4 mm, and then a Cu layer was electroplated on all 4 sides of the conductor – the Cu layer was 20  $\mu$ m-thick all around the tape (samples B3 and B4).

### B. Transverse-compressive-stress apparatus

Each sample was cut to a length of 25 mm. Two copper leads were attached to the tape ends and a pair of voltage taps soldered to its middle. One of the current leads was stationary and the other was free to flex so as to ensure a stress-free cooling of the sample from room temperature to liquid-

nitrogen temperature [10]. The sample was positioned at the bottom end of the apparatus between two flat stainless-steel anvils used to apply transverse compressive stress to the specimen [6]. The load was transmitted to the sample via a stainless steel rod, attached to a calibrated 13 kN load cell at the top end of the apparatus to measure the applied force. During measurements, the bottom anvil was in direct contact with the back of the sample (substrate side), while the top anvil was positioned in the middle area of the tape between the voltage taps. Uniformity of stress over the pressed area of the conductor was achieved by attaching the top anvil to a biaxially gimbaled pressure-foot so that this anvil conforms precisely to the bottom anvil and sample surfaces [6]. Furthermore the top anvil was made wider than the tape and its edges beveled in order to avoid stress concentrations.

## C. Measurement Procedure

During the cooling of the specimen to the liquid-nitrogen temperature of 76 K, the top anvil was not in contact with the sample in order to avoid applying load to the tape during the cooling. Once the sample is cooled, the top anvil is lowered to make contact with the conductor. Transverse compressive stress  $\sigma_T$  is then applied and gradually increased, and voltage-current (*V-I*) curves measured for various values of stress in order to estimate the effect of static compressive stress on  $J_c$ . In this process, we only used the *monotonic-loading* mode [4]-[7], which consists of applying stress to the sample and

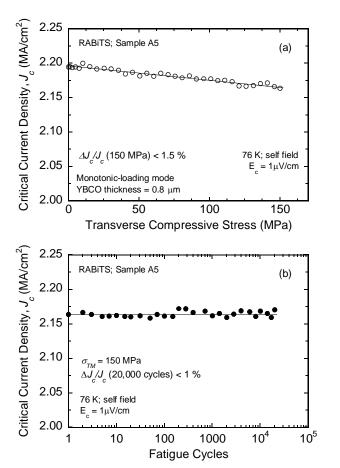


Fig. 1. Dependence of critical-current density  $J_{\rm c}$  on (a) transverse compressive stress and (b) fatigue cycling up to 150 MPa and 20,000 cycles, in a neutral-axis YBCO RABiTS slit coated-conductor. Both effects are negligible, showing that transverse compression and fatigue cycling do not exacerbate edge cracks induced by conductor slitting.

incrementally increasing it without releasing the load between measurements steps, up to a certain maximum value of stress  $\sigma_{TM}$  at which the sample will be subsequently subjected to fatigue cycling. As we showed elsewhere [4]-[7], the monotonic-loading mode generates the least degradation of  $J_c$ (and hence the least cracks) as compared to the *load-unload* or lift-off modes, where the force is released between the measurements steps, and the top anvil is either kept in physical contact with the sample (load-unload mode) or separated from it (*lift-off* mode). Differences between the three modes stem from the fact that, in the monotonic-loading, the pressing anvils provide good frictional support to the specimen, and hence limit formation of mechanical defects [4]-[7]. The aim of using the monotonic-loading mode in this experiment was to avoid inducing new mechanical cracks in the YBCO layer (other than those formed from tape slitting) from the stress build-up before the start of fatigue cycling. This procedure would ascribe the effect of fatigue cycling almost exclusively to the propagation of cracks that originated from conductor slitting.

Once the maximum stress  $\sigma_{TM}$  is reached, the load was cycled between  $\sigma_{TM}$  and near zero at a frequency of 1 Hz, and V-I measurements taken at various stages of fatigue cycling.

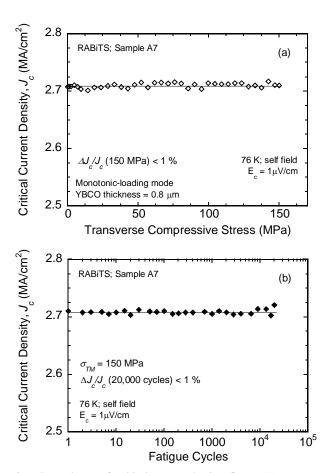


Fig. 2. Dependence of critical-current density  $J_{\rm c}$  on (a) transverse compressive stress and (b) fatigue cycling up to 150 MPa and 20,000 cycles, in a 3-ply YBCO RABiTS slit coated-conductor. Both effects are negligible, again showing that transverse compression and fatigue cycling do not exacerbate edge cracks induced by conductor slitting.

The number of fatigue cycles used ( $\sim 20,000$ ) was 10 times more than that in our previous reports [4]-[6].

All data were acquired in self-field. Values of critical-current  $I_c$  were determined from V-I curves at an electrical-field criterion  $E_c$  of 1  $\mu$ V/cm. Determinations of  $I_c$  and transverse compressive stress were accurate to within 1 % and 3 %, respectively. Values of  $J_c$  were calculated from those of  $I_c$  by using the cross-sectional area of the YBCO layer. The uncertainty in the YBCO cross-section was about 10 %.

### III. RESULTS AND DISCUSSION

A succinct summary of the results obtained is depicted in the last four columns of Table I, where the total degradation of  $J_c$  from the static stress application, and then the subsequent fatigue testing to ~ 20,000 cycles, is tabulated for all samples measured. More detailed descriptions of the effect of the monotonic-loading of transverse compression and fatigue cycling on  $J_c$  is shown for selected samples in Figs.1-4 for both RABiTS and IBAD YBCO coated conductors.

The effect of the monotonic build-up of stress to  $\sigma_{\rm TM}$  has minimal effect on  $J_{\rm c}$  (Figs. 1a and 2a): 1.4 % in the case of sample A5, and nonexistent in sample A7. This shows that our

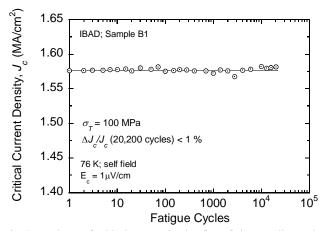


Fig. 3. Dependence of critical-current density  $J_{\rm c}$  on fatigue cycling under transverse compressive stress up to 100 MPa and 20,200 cycles, in a non Cuplated YBCO IBAD slit coated-conductor. The fatigue effect is negligible, showing that propagation of edge cracks induced by conductor slitting is extremely limited.

goal to minimize formation of new cracks before fatigue cycling was achieved for all samples measured (see also Table I). This also confirms that transverse compression has little intrinsic effect on  $J_{\rm c}$  of YBCO, possibly due to the fact that the critical temperature  $T_{\rm c}$  does not change significantly from compressing the YBCO lattice along the c-axis [11].

The effect of fatigue cycling is depicted in Figs. 1b and 2b for the RABiTS neutral-axis and 3-ply architectures, and in Figs. 3 and 4 for the IBAD conductors with and without a Cuplated layer. All data obtained show that, independently of RABiTS or IBAD, conductor geometry, or the sequence of Cu addition and tape slitting, fatigue cycles under transverse compressive stress up to 150 MPa and 20,000 cycles have negligible effect on the transport properties of YBCO conductors. Hence, under this experimental mode, cracks generated at the tape edges from slitting do not get exacerbated and their propagation into the conductor is extremely limited. In short, static and cyclic transverse compressive force does not seem to present a problem for coated-conductor applications, at least up to 150 MPa and 20,000 cycles.

# IV. CONCLUSION

Several YBCO RABiTS and IBAD slit conductors were investigated under transverse compressive stress up to 150 MPa and 20,000 fatigue cycles. Specimens studied had different geometries and fabrication procedures. Independent of the fabrication technique, the data demonstrate that damage at the conductor edges from slitting does not become worse under the experimental conditions that simulate applications such as industrial magnets.

The negligible effect of fatigue in slit samples shows the robustness of the coated conductors under these specific experimental conditions. Nevertheless, the results obtained do not guarantee that slitting is harmless to the conductor performance under all circumstances. Slitting may still weaken the conductor under other mechanical stresses such as

transverse tension [12] or during thermal cycling.

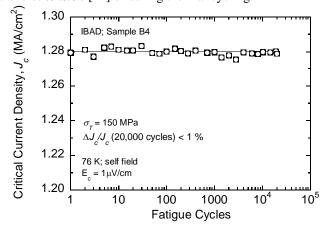


Fig. 4. Dependence of critical-current density  $J_{\rm c}$  on fatigue cycling under transverse compressive stress up to 150 MPa and 20,000 cycles, in a Cuplated YBCO IBAD slit coated-conductor. Again, the fatigue effect is negligible, showing that propagation of edge cracks induced by conductor slitting is extremely limited.

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